APPENDIX E: TEST SEQUENCES

- 1. Test sequence is generated based on below parameters of the DUT:
 - a. Measured maximum power (P_{max})
 - b. Measured Tx_power_at_SAR_design_target (Plimit)
 - c. Reserve_power_margin (dB)
 - P_{reserve} (dBm) = measured P_{limit} (dBm) Reserve_power_margin (dB)
 - d. SAR_time_window (100s for FCC)
- 2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power = P_{max} ; low power = $P_{max}/2$, and the transition occurs after 80 seconds at high power P_{max} . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower P_{limit} for this test. The Test sequence 1 waveform is shown below:

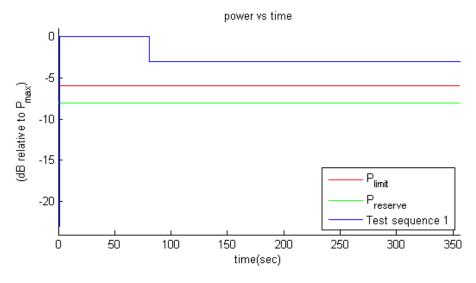


Figure E-1 Test sequence 1 waveform

	FCC ID: A3LSMG996U	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX E:
	10/22/2020 - 12/05/2020	Portable Handset		Page 1 of 3
© 202	0 PCTEST			REV 1.0 04/06/2020

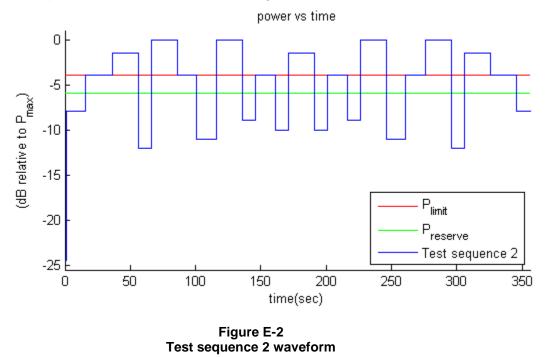
3. Test Sequence 2 Waveform:

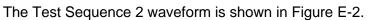
Based on the parameters described above, the Test Sequence 2 is generated as described in Table 10-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

Time duration (seconds)	dB relative to <i>P_{limit}</i> or <i>P_{reserve}</i>	
<mark>15</mark>	P _{reserve} – 2	
20	P _{limit}	
20	(<i>P_{limit}</i> + <i>P_{max})/</i> 2 averaged in mW and rounded to nearest 0.1 dB step	
<mark>10</mark>	P _{reserve} – 6	
<mark>20</mark>	P _{max}	
<mark>15</mark>	P _{limit}	
<mark>15</mark>	P _{reserve} – 5	
20	P _{max}	
<mark>10</mark>	P _{reserve} – 3	
<mark>15</mark>	P _{limit}	
<mark>10</mark>	P _{reserve} – 4	
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step	
10	P _{reserve} – 4	
<mark>15</mark>	P _{limit}	
<mark>10</mark>	P _{reserve} – 3	
20	P _{max}	
<mark>15</mark>	P _{reserve} – 5	
<mark>15</mark>	P _{limit}	
20	P _{max}	
<mark>10</mark>	P _{reserve} – 6	
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step	
20	P _{iimit}	
<mark>15</mark>	P _{reserve} – 2	

Table E-1 Test Sequence 2

	FCC ID: A3LSMG996U	PRT 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX E:
	10/22/2020 - 12/05/2020	Portable Handset		Page 2 of 3
© 202	20 PCTEST			REV 1.0 04/06/2020





	FCC ID: A3LSMG996U		C Approved by: Quality Manager
	Test Dates:	DUT Type:	APPENDIX E:
	10/22/2020 - 12/05/2020	Portable Handset	Page 3 of 3
202	0 PCTEST		REV 1.0 04/06/2020

©